

TENTATIVE

TOSHIBA GATE TURN-OFF THYRISTOR

# SG3000GXH23

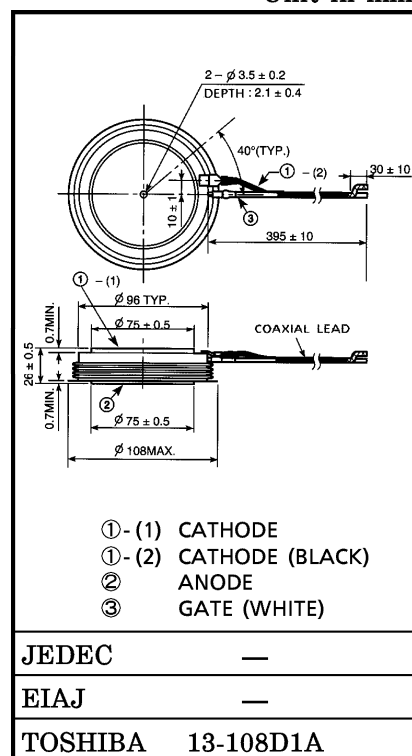
INVERTER APPLICATION

Unit in mm

- Repetitive Peak Off-State Voltage :  $V_{DRM} = 4500 \text{ V}$
- R.M.S On-State Current :  $I_T(\text{RMS}) = 1200 \text{ A}$
- Peak Turn-Off Current :  $I_{TGQM} = 3000 \text{ A}$
- Critical Rate of Rise of On-State Current :  $di/dt = 400 \text{ A}/\mu\text{s}$
- Critical Rate of Rise of Off-State Voltage :  $dv/dt = 1000 \text{ V}/\mu\text{s}$
- Suitable for 3000 V DC Off-State Voltage Application

MAXIMUM RATINGS ( $T_a = 25^\circ\text{C}$ )

CHARACTERISTIC	SYMBOL	RATING	UNIT
Repetitive Peak Off-State Voltage (Note 1)	$V_{DRM}$	4500	V
Repetitive Peak Reverse Voltage	$V_{RRM}$	17	V
Peak Turn-Off Current (Note 2)	$I_{TGQM}$	3000	A
R.M.S On-State Current (Note 3)	$I_T(\text{RMS})$	1200	A
Peak One Cycle Surge On-State Current (Non Repetitive, 10 ms-Width Half Sine Waveform)	$I_{TSM}$	16000	A
Critical Rate of Rise of On-State Current (Note 4)	$di/dt$	400	A / $\mu\text{s}$
Peak Forward Gate Current	$I_{FGM}$	100	A
Average Forward Gate Power Dissipation	$P_{FG}(\text{AV})$	50	W
Average Reverse Gate Power Dissipation	$P_{RG}(\text{AV})$	150	W
R.M.S Gate Current (Note 5)	$I_G(\text{RMS})$	42	A
Peak Reverse Gate Voltage (at Static)	$V_{RGM}$	17	V
Operating Junction Temperature Range	$T_j$	-40~125	$^\circ\text{C}$
Storage Temperature Range	$T_{stg}$	-40~150	$^\circ\text{C}$
Mounting Force	—	28.5~44.0	kN



Weight : 1290 g

(Note 1) :  $V_{GK} = -2 \text{ V}$ (Note 2) :  $V_{DM} = 4500 \text{ V}$ ,  $C_S \geq 3 \mu\text{F}$ ,  $R_S = 5 \Omega$ ,  $di_{GQ}/dt = 50 \text{ A}/\mu\text{s}$ ,  $V_{DSP} \leq 850 \text{ V}$ ,  $L_S = 200 \text{ nH}$  (Stray inductance of snubber [GTO-C<sub>S</sub>-D<sub>S</sub>] loop)(Note 3) : 50 Hz Half Sine Waveform at  $T_f = 76^\circ\text{C}$ (Note 4) :  $V_D = 3000 \text{ V}$ ,  $I_{GM} \geq 25 \text{ A}$ (Note 5) : Ambient Temperature of coaxial Gate-Cathode lead =  $90^\circ\text{C}$ 

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## ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT
Repetitive Peak Off-State Current	$I_{\text{DRM}}$	$V_{\text{DRM}} = 4500 \text{ V}$ , $V_{\text{GK}} = -2 \text{ V}$ , $T_j = 125^\circ\text{C}$	—	—	100	mA
Repetitive Peak Reverse Current	$I_{\text{RRM}}$	$V_{\text{RRM}} = 17 \text{ V}$ , $T_j = 125^\circ\text{C}$	—	—	10	mA
Repetitive Peak Reverse Gate Current	$I_{\text{RGM}}$	$V_{\text{RGM}} = 17 \text{ V}$ , $T_j = 125^\circ\text{C}$	—	—	10	mA
Peak On-State Voltage	$V_{\text{TM}}$	$I_{\text{TM}} = 3000 \text{ A}$ , $T_j = 125^\circ\text{C}$	—	—	4.0	V
Gate Trigger Voltage	$V_{\text{GT}}$	$V_{\text{D}} = 24 \text{ V}$ , $R_{\text{L}} = 0.1 \Omega$	$T_j = -40^\circ\text{C}$	—	—	V
			$T_j = 25^\circ\text{C}$	—	1.5	
Gate Trigger Current	$I_{\text{GT}}$		$T_j = -40^\circ\text{C}$	—	—	A
			$T_j = 25^\circ\text{C}$	—	1.8	
Turn-On Delay Time	$t_{\text{d}}$	$V_{\text{D}} = 3000 \text{ V}$ , $di/dt = 400 \text{ A} / \mu\text{s}$ , $I_{\text{TM}} = 3000 \text{ A}$ , $I_{\text{GM}} = 25 \text{ A}$ , $T_j = 25^\circ\text{C}$	—	—	3	$\mu\text{s}$
Turn-On Time	$t_{\text{gt}}$		—	—	10	$\mu\text{s}$
Critical Rate of Rise of Off-State Voltage	$dv/dt$	$V_{\text{D}} = 3000 \text{ V}$ , $V_{\text{GK}} = -2 \text{ V}$ , Exponential Rise, $T_j = 125^\circ\text{C}$	1000	—	—	$\text{V} / \mu\text{s}$
Storage Time	$t_{\text{s}}$	$I_{\text{TGQ}} = 3000 \text{ A}$ , $V_{\text{DM}} = 4500 \text{ V}$ , $C_{\text{S}} = 6 \mu\text{F}$ , $V_{\text{D}} \leq 3000 \text{ V}$ , $R_{\text{S}} = 5 \Omega$ , $di_{\text{GQ}}/dt = 50 \text{ A} / \mu\text{s}$ , $T_j = 125^\circ\text{C}$ , $V_{\text{DSP}} \leq 850 \text{ V}$	—	—	30	$\mu\text{s}$
Gate Turn-Off Time	$t_{\text{gg}}$		—	—	33	$\mu\text{s}$
Tail Time	$t_{\text{tail}}$		—	—	115	$\mu\text{s}$
Gate Turn-Off Current	$I_{\text{GQ}}$		—	—	770	A
Thermal Resistance	$R_{\text{th(j-f)}}$	(Junction to Fin)	—	—	0.014	$^\circ\text{C} / \text{W}$

(Note) : The switching loss value is different from SG3000GXH29.

$E_{\text{OFF}}$  is about 0.7 times as SG3000GXH29.

$E_{\text{ON}}$  is same as SG3000GXH29.

